

ON Semiconductor®

## FDZ451PZ

# P-Channel 1.5 V Specified PowerTrench® Thin WL-CSP MOSFET -20 V, -2.6 A, 140 mΩ

#### **Features**

- Max  $r_{DS(on)}$  = 140 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -2 A
- Max  $r_{DS(on)} = 182 \text{ m}\Omega$  at  $V_{GS} = -2.5 \text{ V}$ ,  $I_D = -1.5 \text{ A}$
- Max  $r_{DS(on)}$  = 231 m $\Omega$  at  $V_{GS}$  = -1.8 V,  $I_D$  = -1 A
- Max  $r_{DS(on)} = 315 \text{ m}\Omega$  at  $V_{GS} = -1.5 \text{ V}$ ,  $I_D = -1 \text{ A}$
- Occupies only 0.64 mm<sup>2</sup> of PCB area. Less than 16% of the area of 2 x 2 BGA
- Ultra-thin package: less than 0.4 mm height when mounted
- HBM ESD protection level > 2 kV (Note3)
- RoHS Compliant



Designed on ON Semiconductor advanced 1.5 V PowerTrench® process with state of the art "fine pitch" Thin WLCSP packaging process,

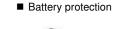
the FDZ451PZ minimizes both PCB space and r<sub>DS(on)</sub>. WLCSP MOSFET embodies advanced breakthrough in packaging technology which enables the device to combine excellent thermal transfer characteristics, ultra-low profile (0.4

mm) and small (0.8x0.8 mm<sup>2</sup>) packaging, low gate charge, and low  $r_{DS(on)}$ .

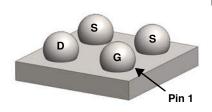
# Applications Battery management

- Load switch

TOP







**BOTTOM** 

#### WL-CSP 0.8X0.8 Thin

## MOSFET Maximum Ratings T<sub>A</sub> = 25 °C unless otherwise noted

Symbol	Parai	meter		Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			-20	V
V <sub>GS</sub>	Gate to Source Voltage			±8	V
I <sub>D</sub>	-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	-2.6	
	-Pulsed			-10	Α
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1a)	1.3	14/
	Power Dissipation	T <sub>A</sub> = 25°C	(Note 1b)	0.4	W
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temper	rature Range		-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	93	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	(Note 1b)	311	C/VV

### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
EH	FDZ451PZ	WL-CSP 0.8X0.8 Thin	7 "	8 mm	5000 units

# **Electrical Characteristics** $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
$BV_{DSS}$	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		-13		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -16 V, V <sub>GS</sub> = 0 V			-1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	$V_{GS} = \pm 8 \text{ V}, V_{DS} = 0 \text{ V}$			±10	μΑ

#### **On Characteristics**

V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.3	-0.7	-1.2	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		2.5		mV/°C
		$V_{GS} = -4.5 \text{ V}, I_D = -2 \text{ A}$		108	140	
		$V_{GS} = -2.5 \text{ V}, I_D = -1.5 \text{ A}$		129	182	
r <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = -1.8 \text{ V}, I_D = -1 \text{ A}$		159	231	mΩ
		$V_{GS} = -1.5 \text{ V}, I_D = -1 \text{ A}$		201	315	
		$V_{GS} = -4.5 \text{ V}, I_D = -2 \text{ A}, T_J = 125 ^{\circ}\text{C}$		143	204	
9 <sub>FS</sub>	Forward Transconductance	$V_{DD} = -5 \text{ V}, I_{D} = -2 \text{ A}$		7.8		S

### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 10 V V 0 V	416	555	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	61	80	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 1011 12	53	70	pF

### **Switching Characteristics**

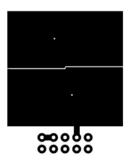
$t_{d(on)}$	Turn-On Delay Time		4.9	10	ns
t <sub>r</sub>	Rise Time	$V_{DD} = -10 \text{ V}, I_D = -2.5 \text{ A},$	6.3	13	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$	68	108	ns
t <sub>f</sub>	Fall Time		33	52	ns
$Q_g$	Total Gate Charge	45,474	6.3	8.8	nC
Q <sub>gs</sub>	Gate to Source Charge	$V_{GS} = -4.5 \text{ V}, V_{DD} = -10 \text{ V},$ $I_{D} = -2.5 \text{ A}$	0.6		nC
$Q_{gd}$	Gate to Drain "Miller" Charge	ID = -2.5 A	1.7		nC

### **Drain-Source Diode Characteristics**

$V_{SD}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -1.4 \text{ A}$ (Note 2)		-0.9	-1.2	V
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = -2.5 A, di/dt = 100 A/μs		29	46	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = -2.5 A, α//ατ = 100 A/μs		10	18	nC

#### Notes:

1. R<sub>0,A</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0,C</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



 a. 93 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 311 °C/W when mounted on a minimum pad of 2 oz copper.

- 2. Pulse Test: Pulse Width <  $300\mu s$ , Duty cycle < 2.0%.
- 3. The diode connected between the gate and source serves only as protection ESD. No gate overvoltage rating is implied.

## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

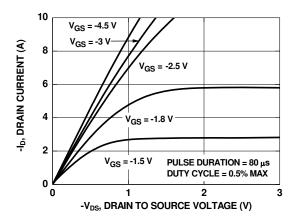


Figure 1. On-Region Characteristics

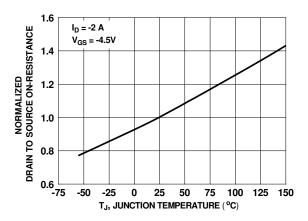


Figure 3. Normalized On-Resistance vs Junction Temperature

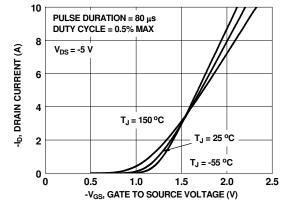


Figure 5. Transfer Characteristics

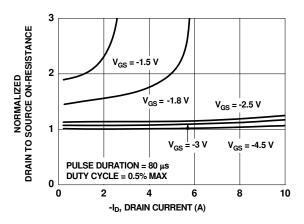


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

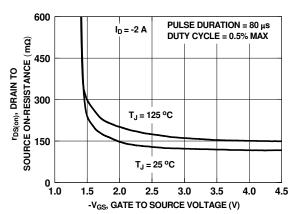


Figure 4. On-Resistance vs Gate to Source Voltage

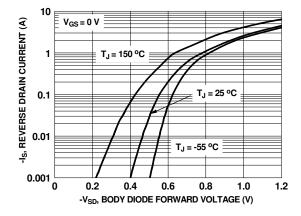


Figure 6. Source to Drain Diode Forward Voltage vs Source Current



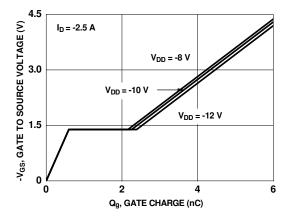


Figure 7. Gate Charge Characteristics

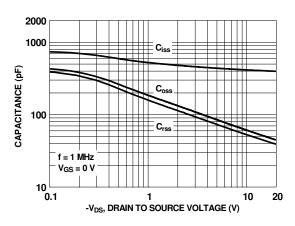


Figure 8. Capacitance vs Drain to Source Voltage

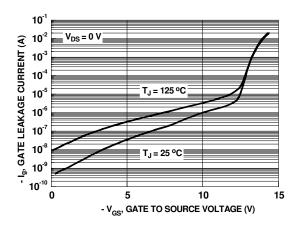


Figure 9. Gate Leakage Current vs Gate to Source Voltage

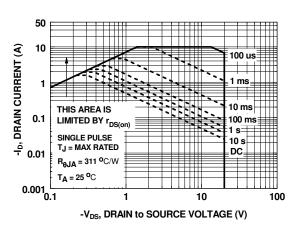


Figure 10. Forward Bias Safe Operating Area

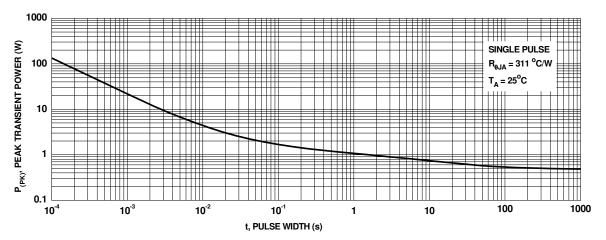


Figure 11. Single Pulse Maximum Power Dissipation



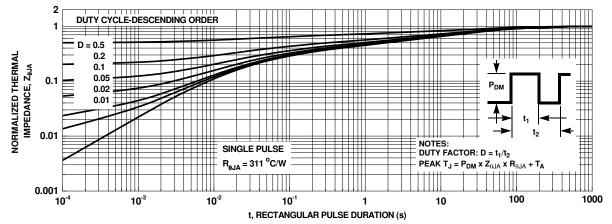
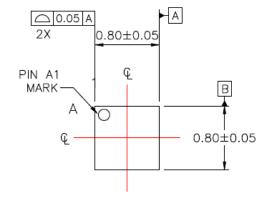
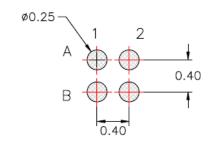


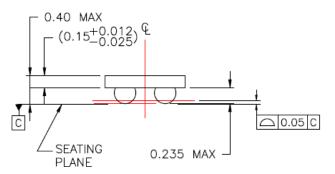
Figure 12. Junction-to-Ambient Transient Thermal Response Curve

## **Dimensional Outline and Pad Layout**

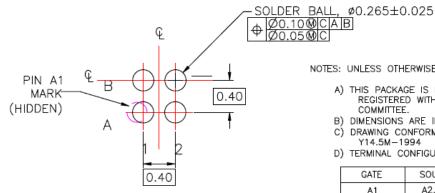




△ 0.05 B 2X



LAND PATTERN RECOMMENDATION



NOTES: UNLESS OTHERWISE SPECIFIED

- A) THIS PACKAGE IS NOT PRESENTLY REGISTERED WITH ANY STANDARDS COMMITTEE.
- B) DIMENSIONS ARE IN MILLIMETERS.
- C) DRAWING CONFORMS TO ASME Y14.5M-1994
- D) TERMINAL CONFIGURATION TABLE:

GATE	SOURCE	DRAIN
A1	A2, B2	B1

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